

EL2243D Die

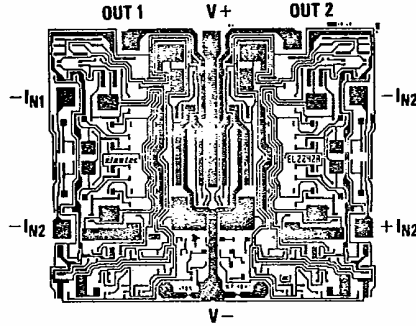
Dual Fast Single-Supply Decompensated Op-Amp

EL2243D

T-79-10

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$)

Voltage between $V+$ and $V-$	36V
Voltage between $-IN$ or $+IN$ Pins	36V
Voltage at $-IN$ or $+IN$ Pins	$V+$ to $V-$
Output Current	50 mA (Peak)
	30 mA (Continuous)
Current into $+IN$, $-IN$	5 mA



DIE SIZE: 86 x 72 MILS

Important Note:

For AC electrical characteristics, refer to the typical electrical table and performance curves in the package data sheet. These characteristics are guaranteed but not tested in die form. Unless otherwise noted, all tests are pulsed tests, therefore $T_J = T_C = T_A$.

Test Level	Test Procedure
I	100% production tested in wafer form. See remarks under Electrical Testing in the General Die section.

DC Electrical Characteristics $V_S = \pm 15, R_L = 1 \text{ k}\Omega, T_A = 25^\circ\text{C}$

Parameter	Description	Min	Typ	Max	Test Level	Units
V_{OS}	Offset Voltage		1.5	5	I	mV
I_B	Bias Current		0.5	0.7	I	μA
I_{OS}	Offset Current		0.01	0.1	I	μA
V_{CM+}	Common Mode Range	12	13.3		I	V
V_{CM-}	Common Mode Range	-15	-15.3		I	V
A_{VOL}	Large Signal Voltage Gain (Note 1)	250	500		I	V/mV
CMRR	Common-Mode Rejection Ratio (Note 2)	80	100		I	dB
V_O	Output Voltage Swing R_L tied to $V-$	± 12	± 13.5		I	V
		-14.98	-15		I	V
I_O	Output Current (Note 4)	± 15	± 25	± 50	I	mA
I_S	Supply Current		8.2	10	I	mA
PSRR	Power Supply Rejection Ratio (Note 3)	80	100		I	dB

Note 1: $V_O = \pm 10V$.

Note 2: Two tests are performed with $V_{CM} = 0V$ to $-12V$ and $V_{CM} = 0V$ to $12V$.

Note 3: Two tests are performed with $V+ = +3V$, $V-$ is changed from $-2V$ to $-27V$. $V- = -2V$, $V+$ is changed from $3V$ to $28V$.

Note 4: The inputs are overdriven by $\pm 15V$ and the output $R_L = 100\Omega$.



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